

Title (en)

X-ray optical system and method for imaging a source

Title (de)

Röntgen-optisches System und Verfahren zur Abbildung einer Quelle

Title (fr)

Système optique à rayons X et méthode pour former un image d'une source

Publication

EP 1318524 A3 20070704 (DE)

Application

EP 02026625 A 20021129

Priority

DE 10160472 A 20011208

Abstract (en)

[origin: EP1318524A2] The system has two x-ray reflectors (A,B) for focussing an x-ray source (S) onto a target region. The x-ray reflectors are tilted towards each other, with an offset from 90 degrees so that the combined acceptance region of the x-ray reflectors is matched to the shape of the x-ray source and/or the target region. The offset from 90 degrees is preferably between 30 and 85 degrees. The x-ray reflectors may comprise a multilayer structure. Independent claims are also included for the following: (1) an x-ray diffractometer; and (2) a method of focusing an image source for x-ray or neutron radiation onto a target region.

IPC 8 full level

G21K 1/06 (2006.01)

CPC (source: EP US)

G21K 1/06 (2013.01 - EP US)

Citation (search report)

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EP1791135A3; EP1791135A2; US10153062B2

Designated contracting state (EPC)

AT BE BG CH CY CZ DE DK EE ES FI FR GB GR IE IT LI LU MC NL PT SE SK TR

Designated extension state (EPC)

AL LT LV MK RO SI

DOCDB simple family (publication)

EP 1318524 A2 20030611; EP 1318524 A3 20070704; EP 1318524 B1 20090318; DE 10160472 A1 20030626; DE 10160472 B4 20040603; US 2003108153 A1 20030612; US 6925147 B2 20050802

DOCDB simple family (application)

EP 02026625 A 20021129; DE 10160472 A 20011208; US 30291802 A 20021125